

## NO. 3 ESS TEST PROGRAM (X-RAY) TESTS

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1. GENERAL INFORMATION

1.1 Description

1.11 This section contains information covering the operation of the No. 3 ESS Processor and Peripheral Test Programs.

1.12 This section also provides information regarding cleaning of the KS-21447, L2 Mini Recorders which must be done prior to inserting any tape cartridge into either Mini Recorder.

1.13 Test programs are contained on tape cartridge TP-592600 and are to be loaded into memory via the Tape Data Controller (TDC) Units under control of the 3ACC.

1.2 References

1.21 The following documents will be useful as references during the execution of the test programs.

<u>Document</u>	<u>Title</u>
PA-592601	Program Application - No. 3 ESS X-Ray Programs
PG-592601	No. 3 ESS X-Ray Programs Index of X-Ray Program Documents for Factory and Initial Installation Testing
SD-1A329-01	Remreed Network Circuit Pack Schematic
SD-1C900-01	3A Central Control Circuit Schematic
CD-1C900-01	3A Central Control Circuit Description

SD-1C901-01	3ACC Control Panel Circuit Schematic
CD-1C901-01	3ACC Control Panel Circuit Description
SD-1C902-03	Main Store Controller and Memory Circuit Schematic
CD-1C902-03	Main Store Controller and Memory Circuit Description
SD-1C904-01	Tape Data Controller Circuit Schematic
CD-1C904-01	Tape Data Controller Circuit Description
SD-1C905-01	Teletypewriter Controller Circuit Schematic
CD-1C905-01	Teletypewriter Controller Circuit Description
SD-1C906-01	System Status Panel Circuit Schematic
CD-1C906-01	System Status Panel Circuit Description
SD-1C907-01	System Status Panel Controller Circuit Schematic
CD-1C907-01	System Status Panel Controller Circuit Description
SD-1C908-01	System Status Panel Relay Circuit Schematic
CD-1C908-01	System Status Panel Relay Circuit Description

<u>Document</u>	<u>Title</u>	<u>Document</u>	<u>Title</u>
SD-1C909-01	Maintenance Frame Power Circuit Schematic	SD-3H200-01	Junctor and Junctor Control Circuit Schematic
CD-1C909-01	Maintenance Frame Power Circuit Description	CD-3H200-01	Junctor and Junctor Control Circuit Description
SD-1C910-02	Processor Frame Circuit Schematic	SD-3H520-01	Peripheral Test Circuit Schematic
CD-1C910-02	Processor Frame Circuit Description	CD-3H520-01	Peripheral Test Circuit Description
SD-1C911-02	Processor Frame Power Circuit Schematic	SD-3H901-01	Network Frame Circuit Schematic
CD-1C911-02	Processor Frame Power Circuit Description	CD-3H901-01	Network Frame Circuit Description
SD-1C912-01	Maintenance Frame Circuit Schematic	SD-3H902-01	Control Frame Circuit Schematic
CD-1C912-01	Maintenance Frame Circuit Description	CD-3H902-01	Control Frame Circuit Description
SD-1C913-01	Electronic Remreed Pulser Circuit Schematic	SD-3H912-01	Scanner, Peripheral Pulse Distributor and Peripheral Decoder Assignment Rules
CD-1C913-01	Electronic Remreed Pulser Circuit Description	SD-81885-01	Power Systems Signaling Circuit - Circuit Pack Schematic
SD-3H110-01	Peripheral Controller Circuit Schematic	SD-82156-01	Ringling, Tone and Signaling Circuits General Use Circuit Packs
CD-3H110-01	Peripheral Controller Circuit Description	SD-82255-01	Ringling, Tone and Signaling Circuit Schematic
SD-3H120-01	15A Grid Circuit Schematic	SD-82255-01	Ringling, Tone and Signaling Circuit Description
CD-3H120-01	15A Grid Circuit Description	SD-99303-01	400A Tone Generator Circuit Schematic
SD-3H121-01	First and Second Stage Access Circuit Schematic	SD-99303-01	400A Tone Generator Circuit Description
CD-3H121-01	First and Second Stage Access Circuit Description		
SD-3H122-01	15B Grid Circuit Schematic		
CD-3H122-01	15B Grid Circuit Description		
SD-3H130-01	15C Grid Circuit Schematic		
CD-3H130-01	15c Grid Circuit Description		
SD-3H131-01	Third Stage Access Circuit Schematic		
CD-3H131-01	Third Stage Access Circuit Description		
SD-3H140-01	Master Scanner Matrix Circuit Schematic		
CD-3H140-01	Master Scanner Matrix Circuit Description		

1.22 Additional Circuit Pack Schematics (CPS) for FA-, FB-, and FC-type circuit packs will also be useful as references.

### 1.3 Test Records

1.31 The results of the test program tests should be recorded on SD-97-1313 and SD-97-1315 forms. Detailed information for completing these forms appears in Handbook 3, Section 6B.

### 1.4 Sequence

#### 1.41 Unitized System

1.411 Processor Test Programs are to be executed following Processor and Maintenance Frame Power

Verification Tests (HB 269, Section 180, paragraphs 3 and 4).

1.412 Peripheral Test Programs are to be executed following Power Verification of all peripheral frames (HB 269, Section 180, paragraphs 5 through 8), and following successful execution of all Processor Test Programs.

1.413 Refer to HB 269, Section 1A for more detailed test sequence information.

1.42 Individual Frame Shipments

1.421 Processor Test Programs are to be executed following Control Complex Power Verification Tests (HB 269, Section 150).

1.422 Peripheral Test Programs are to be executed following Power Verification Tests of Control, Network and Test Frames (HB 269, Sections 160, 161 and 151), and following successful execution of all Processor Test Programs.

1.423 Refer to HB 269, Section 1B for more detailed test sequence information.

2. TEST EQUIPMENT

2.1 Tape Cartridges

2.11 The following tape cartridges are required:

<u>H- Specification</u>	<u>Description</u>
H-460-009	Specification for 2 tape cartridges which provide Processor and Peripheral Test Programs for No. 3 ESS. PG-592601 lists all programs that reside on these cartridges.

→ Arrows indicate new or changed information.

2.2 Test Sets

2.21 The following test sets are required:

<u>Amt.</u>	<u>ITE</u>	<u>Description</u>
1	4659	Volt-Ohm-Milliammeter
1	4669	Tektronix 134 Amplifier and P6020 Current Probe
1	5237B	Oscilloscope Tektronix 465
1	5543	3ACC/Auxiliary Processor Test Accessory Set
1	5653	No. 3 ESS Test Accessory Set

2.22 The following test sets will not be provided as standard equipment. These sets will only be needed if neither 3ACC bootstraps.

<u>Amt.</u>	<u>ITE</u>	<u>Description</u>
1	5511	3ACC Micro Control Test Set
1	5550	3ACC Micro Control X-Ray

3. TEST PREPARATION

3.1 Prior to the first insertion of a tape cartridge into the KS-21447, L2 Mini Recorders, clean the Mini Recorders as described in Handbook 261, Section 445.

NOTE: These cleaning procedures are to be performed monthly between the first cleaning and job turnover.

4. TEST PROCEDURES

4.1 Test Program Tests

4.11 Execute Processor Test Programs according to the instructions in PA-592601.

4.12 Execute Peripheral Test Programs according to the instructions in PA-592601 under "Procedures for Executing Peripheral Test Programs."

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To cancel UIS. PATCH information not required with Issue 2 of TP-592600.